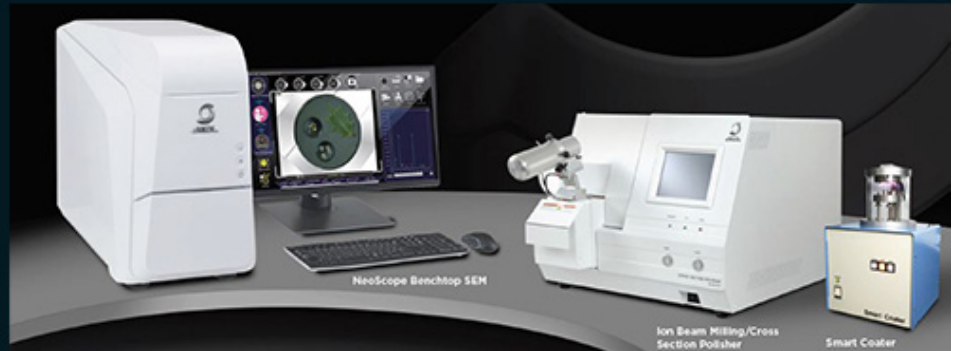


Set the Table with JEOL

Tabletop
Microscopy
Solutions



NeoScope Tabletop Scanning Electron Microscope

The JEOL NeoScope tabletop Scanning Electron Microscopes is simple, flexible, and produces high quality images and analysis - the ideal tabletop solution for many SEM needs. It is simple enough for users at any skill level to obtain outstanding SEM images and elemental analysis results in minutes. It is equipped with a large chamber, high and low vacuum modes, secondary and backscatter electron detectors, real-time 3D imaging, highly-advanced auto functions and the option to add a fully embedded EDS with real-time, 'Live' analysis.

High Speed Ion Beam Milling System - Cryo and Air-Isolation Milling System

The JEOL Cross Section Polisher (CP) is a tabletop milling and polishing system that is ideally suited for preparation of a variety of environment and beam sensitive materials, including metals, polymers, ceramics, Lithium Ion Batteries, and composites. The JEOL CP is proven technology for creating artifact-free cross sections and polished surfaces for a variety of soft and hard samples, including oil shale, paper, and galvanized steel without crumbling, smearing, or distortion of the sample. The CP is the ideal solution for preparing Additive Manufacturing samples for imaging and analysis, and for chemical EDS analysis of materials.

Sputter Coater

The JEOL Smart Coater is a fully automated sputter coater that applies a fine grained gold or platinum (option) coating on samples for imaging in a scanning electron microscope. This simple-to-use sputter coater features fully automated vacuum and sputtering.

Carbon Coater

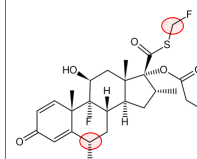
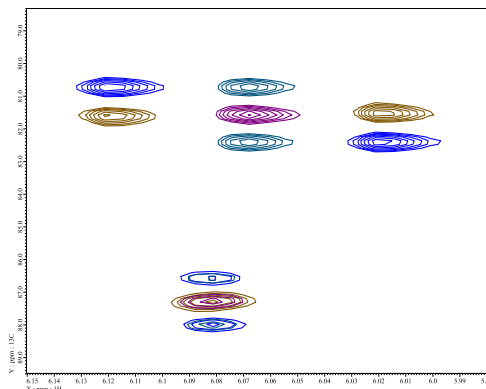
The JEOL Carbon Coater is a fully-automated carbon coater that applies a thin conductive carbon film on a sample surface. Applying this coating to a non-conductive sample is an effective preparation technique for eliminating charge-up artifacts for analysis in a scanning electron microscope. Sample preparation of this type is ideal for X-ray applications (EDS), CL or backscatter electron imaging. This simple to use carbon coater features fully automated vacuum and carbon evaporation.



ROYALPROBE™ HFX

One Probe – No Compromise for NMR analysis of Fluorinated Compounds

The ROYALPROBE™ HFX is the world's first liquid NMR probe with the capability to switch between single tune (1H or 19F) and dual tune (1H and 19F) modes on the high frequency coil. Operating in single tune mode, the ROYALPROBE™ HFX has the same high performance for sensitivity and pulse widths as the current standard JEOL NMR ROYALPROBE. Operating the HFX probe in dual tune mode allows for a wide variety of advanced 1H and 19F NMR experiments including 1H{19F}, 19F{1H}, X{1H,19F}, and many unique X{1H, 19F} correlation experiments to simplify spectral assignments of modern complex fluorine containing compounds for the pharmaceutical and polymer industries. Those advance H,F,X, experiments can be run on a routine 2-channel ECZ spectrometers. The Low Frequency coil can be tuned to any nucleus between 31P and 15N.



¹H-¹³C gHMBCAD
¹⁹F decoupling options
(overlay)

ROYAL HFX Probe

Single Tune HFX Off

Dual Tune HFX On

Rotate Idler Coil

JEOL

To download our Applications Notes and view on-demand webinars visit:

www.jeolusa.com/ENCNMR

